


<b>Search Notes</b>  	<b>Application/Control No.</b>  10537155	<b>Applicant(s)/Patent Under Reexamination</b>  LEE ET AL.
	<b>Examiner</b>  O'Reilly III, Patrick F	<b>Art Unit</b>  3749

SEARCHED			
Class	Subclass	Date	Examiner
454	284, 299, 305	12/20/2006	PFO3
62	186	12/20/2006	PFO3
Above	Updated	7/5/2007	PFO3

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (USPAT, USPGPUB, USOCR, EPO, JPO, DERWENT, IBM_TDB) searched - printout attached.	12/20/2006; 7/5/2007	PFO3
PLUS search performed - printout of search results attached.	12/20/2006	STIC
Inventor name search performed in PALM and EAST.	12/19/2006; 12/21/2006	PFO3

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner